



<b>Session Title:</b>	<b>[WeG2] Frontier Metrology and Modeling IV</b>
<b>Session Date:</b>	<b>November 13 (Wed.), 2024</b>
<b>Session Time:</b>	<b>14:10-15:40</b>
<b>Session Room:</b>	<b>Room G (Meeting Room, 5F, Grand Josun Busan)</b>
<b>Session Chair:</b>	<b>Prof. Kumar Mohit (Ajou Univ., Korea)</b>

**[WeG2-1] [Invited] 14:10-14:40**

### **Metrology and Inspection Challenges for High NA EUV**

Dieter Van den Heuvel, Christophe Beral, Matteo Beggiato, Anne-Laure Charley, Gian Lorusso, Janusz Bogdanowicz, and Hongcheon Yang (imec, Belgium)

**[WeG2-2] [Invited] 14:40-15:10**

### **Optical Metrology Development Trends in Today's Advanced Device Nodes**

Nahee Park (KLA Corp., USA)

**[WeG2-3] [Invited] 15:10-15:40**

### **High NA Objective Lens Optical Design for Metrology & Inspection**

Jun Ho Lee, Ji Yong Joo, Yu Bin Jo, Ji Hyun Park (Kongju Nat'l Univ., Korea), Hagyoung Kihm, Ho-Soon Yang (KRISS, Korea), and Oh-Hyung Kwon (Nextin, Korea)